



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. 10/615,051
Filing Date July 7, 2003
Inventorship Brian A. Vaartstra
Assignee Micron Technology, Inc.
Group Art Unit 2823
Examiner Brook Kebede
Attorney's Docket No. MI22-2308
Customer No. 021567
Title: Methods of Forming a Phosphorus Doped Silicon Dioxide Comprising Layer

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

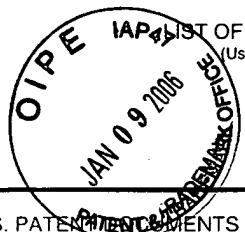
This Request for Continued Examination (RCE) Application is being filed in an abundance of caution to ensure consideration of the references listed on the attached form PTO-1449.

The attached Form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to FEDERAL REGISTER, Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art are attached. No admission is made regarding whether the listed references are prior art.

Respectfully submitted,

Dated: 1-9-06

By: 
Mark S. Matkin
Reg. No. 32,268

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2308		SERIAL NO. 10/615,051		
 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: Brian A. Vaartstra				
		FILING DATE July 7, 2003		GROUP 2823					
U.S. PATENT DOCUMENTS									
*Examiner's Initials		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate	
	AA	2005/0009368	01/05	Vaarstra					
	AB	2005/0112282	05/05	Gordon et al.					
	AC								
	AD								
	AE								
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	AG								
	AH								
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FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country		Class	Subclass	Translation	
								Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
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